

# Recall, carrier densities:

$$n = N_c(T)e^{-(\varepsilon_c - \mu)/kT}$$

$$p = P_v(T)e^{-(\mu - \varepsilon_v)/kT}$$



product  
independent of  $\mu$

$$np = N_c(T)P_v(T)e^{-(\varepsilon_g)/kT}$$

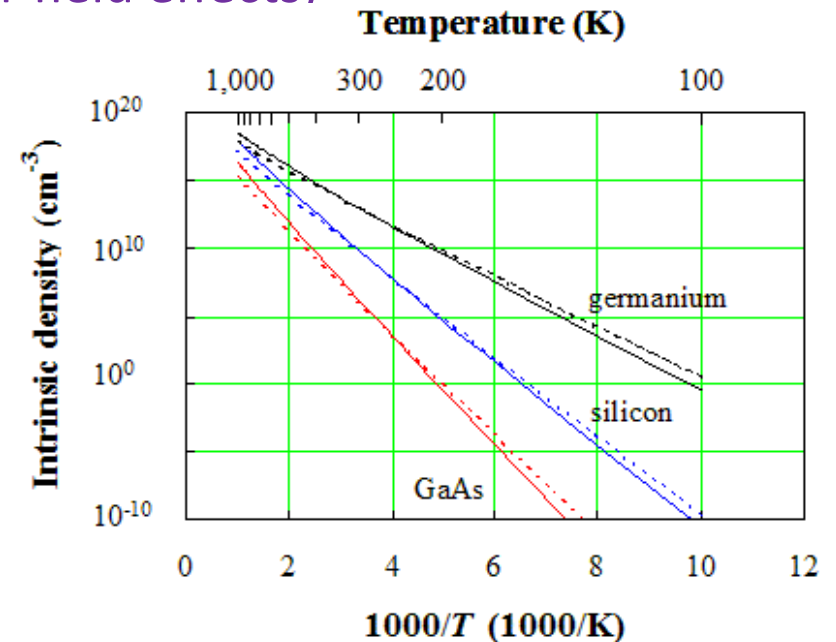
Silicon, RT  $N_c P_v = (2.8 \times 1.0) \times 10^{38} \text{ cm}^{-6}$

$n$  &  $p$  adjusted by changes in  $\mu$ .  
OK far from band edges (used MB approx.)

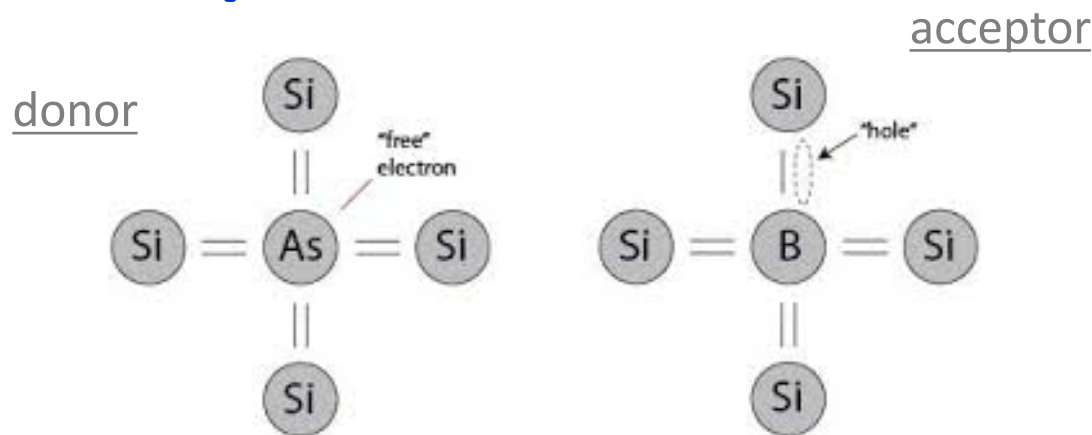
- Intrinsic: ultra-pure (no impurities, or field effects)
- $n = p$  by charge conservation.
- $\mu$  near mid-gap position.

$$n_i = \sqrt{N_c(T)P_v(T)}e^{-(\varepsilon_g)/2kT}$$

Silicon, RT  $n_i = 1.5 \times 10^{10} \text{ cm}^{-3}$



# Donors / acceptors

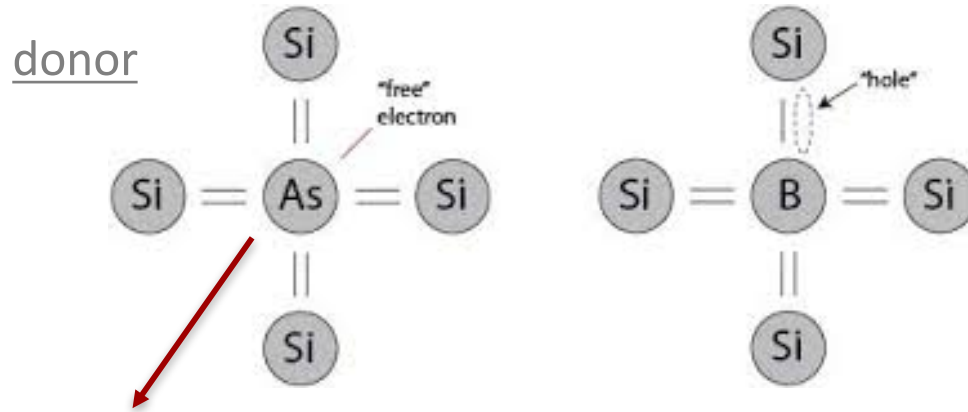


boron 5 <b>B</b> 10.811	carbon 6 <b>C</b> 12.011	nitrogen 7 <b>N</b> 14.007
aluminium 13 <b>Al</b> 26.982	silicon 14 <b>Si</b> 28.086	phosphorus 15 <b>P</b> 30.974
gallium 31 <b>Ga</b> 69.723	germanium 32 <b>Ge</b> 72.61	arsenic 33 <b>As</b> 74.922
indium 49 <b>In</b> 114.82	tin 50 <b>Sn</b> 118.71	antimony 51 <b>Sb</b> 121.76

## impurities:

- Electronic states mixed with band states - *not so important*.
- States in gap: localized.
- **deep traps** (near mid-gap) various practical effects, e.g. pinned chemical potential detrimental to some devices.
- **Shallow donors/acceptors**: similar to hydrogen states.

# Donors / acceptors



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Assume ionized into C.B.

Ground state: localized "Bohr orbit", composed of CB states.

(Result shows this is consistent picture)

$$U = \frac{1}{\kappa} \frac{e^2}{r}$$

$$r = \frac{\hbar^2}{m_c^* e} \kappa \approx 60 a_0$$

$$E_n = 13.6 \text{eV} \frac{m_c^* / m}{\kappa^2} \frac{1}{n^2} \approx \underline{20 \text{meV} / n^2}$$

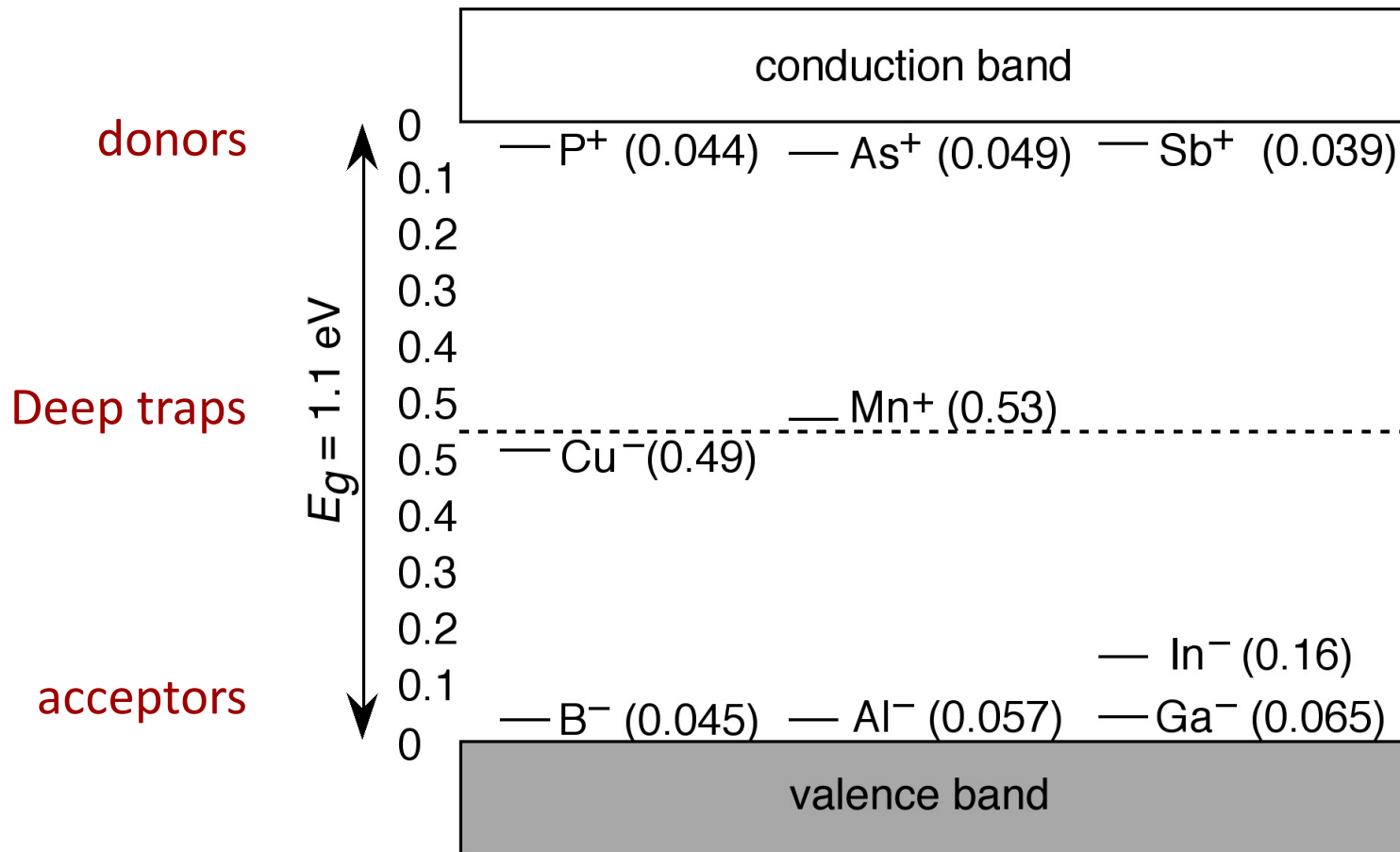
← silicon

But coulomb interactions may limit this to one occupied state (HW)

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Results:



Silicon  
impurity  
states

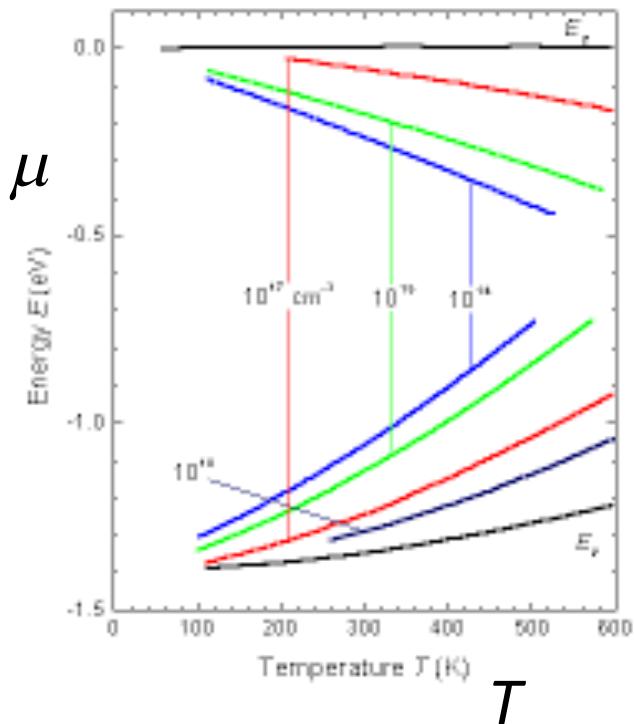
# Donors / acceptors:

Equilibrium :

typically all ionized, wide range of  $T$   
(density not too big)

Donors: pull  $\mu$  toward CB edge.

$$n - p = N_d \left[ 1 - \frac{1}{1 + \frac{1}{2} e^{(\epsilon_d - \mu)/kT}} \right] \quad \text{general case}$$



Notation:

$n$  = electron density (CB)

$p$  = hole density (VB)

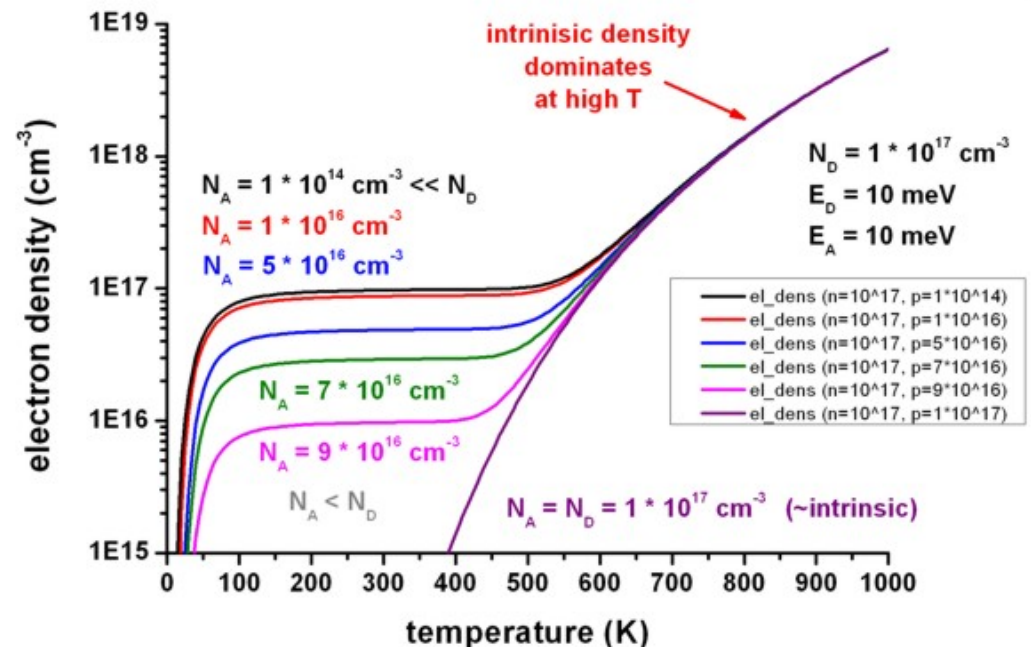
$N_D$  = donor atom density

$n_D$  = density, electrons on donors (*neutral*)

$N_A$  = acceptor atom density

$n_A$  = holes on acceptors

Electron density in Ge vs. temperature for different acceptor densities  $N_A$



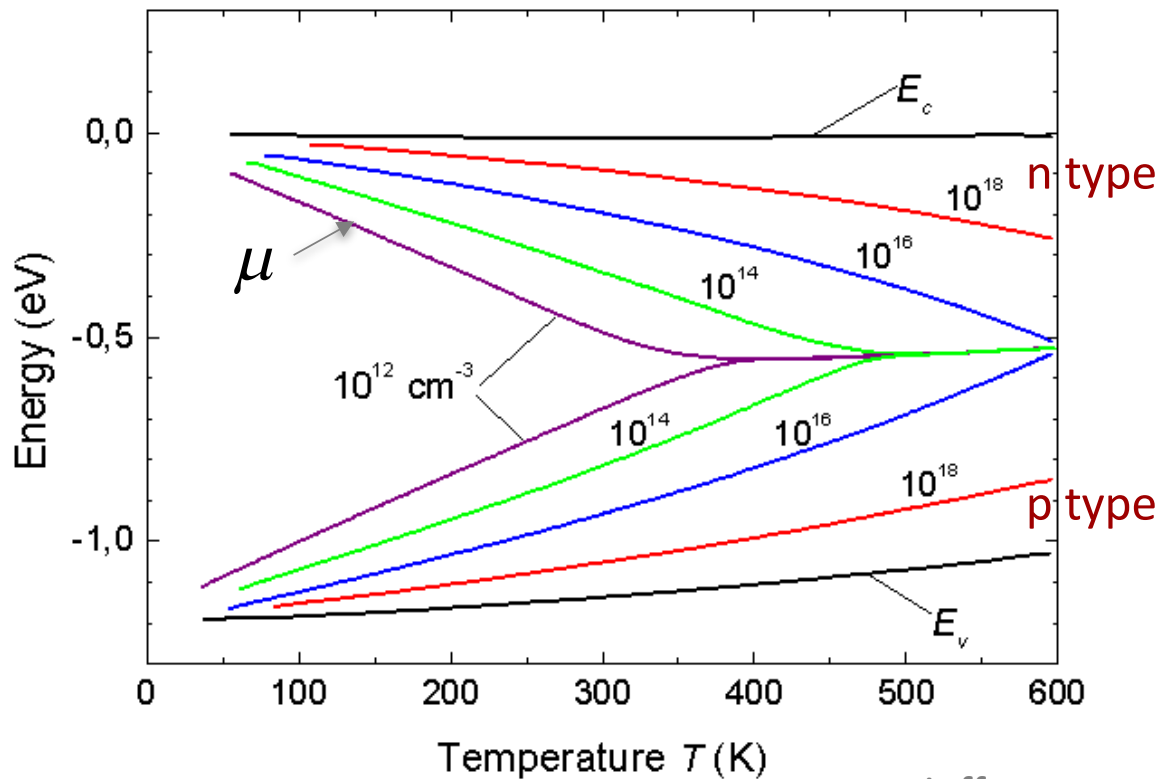
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$$n - p = N_d \left[ 1 - \frac{1}{1 + \frac{1}{2} e^{(\varepsilon_d - \mu)/kT}} \right]$$

$$n \approx N_c(T) e^{-(\varepsilon_c - \mu)/kT}$$

$$p \approx P_v(T) e^{-(\mu - \varepsilon_v)/kT}$$

Solve for  $\mu$ .